TOSHIBA Field Effect Transistor Silicon P Channel MOS Type ( $L^2$ - $\pi$ -MOSV)

## **2SJ377**

# Relay Drive, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

• Low drain–source ON resistance : RDS (ON) = 0.16  $\Omega$  (typ.)

• High forward transfer admittance  $: |Y_{fs}| = 4.0 \text{ S (typ.)}$ 

• Low leakage current  $:I_{DSS} = -100 \mu A \text{ (max) (V}_{DS} = -60 \text{ V)}$ 

• Enhancement mode :  $V_{th} = -0.8 \sim -2.0 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -1 \text{ mA})$ 

#### Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	-60	V	
Drain-gate voltage (Ro	<sub>GS</sub> = 20 kΩ)	$V_{DGR}$	-60	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	I <sub>D</sub>	-5	Α	
	Pulse(Note 1)	I <sub>DP</sub>	-20	Α	
Drain power dissipation	n (Tc = 25°C)	$P_{D}$	20	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	273	mJ	
Avalanche current		I <sub>AR</sub>	-5	Α	
Repetitive avalenche energy (Note 3)		E <sub>AR</sub>	2	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature ra	ange	T <sub>stg</sub>	-55~150	°C	

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	6.25	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	125	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

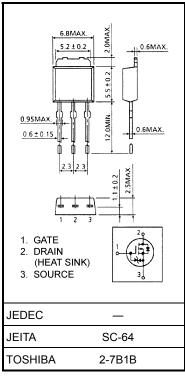
Note 2:  $V_{DD}$  = -25 V,  $T_{ch}$  = 25°C (initial), L = 14.84 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = -5 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

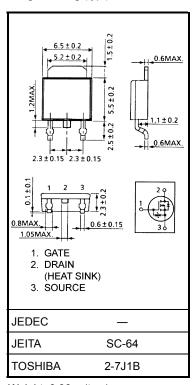
This transistor is an electrostatic-sensitive device.

Please handle with caution.

Unit: mm



Weight: 0.36 g (typ.)



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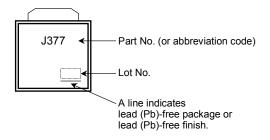
## **Electrical Characteristics (Ta = 25°C)**

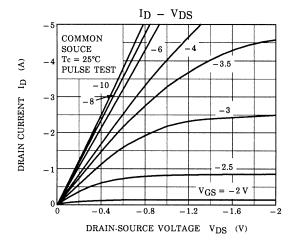
Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V	_	_	-100	μA
Drain-source br	eakdown voltage	V <sub>(BR) DSS</sub>	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-60	_	_	V
Gate threshold v	oltage	$V_{th}$	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-0.8	_	-2.0	V
Drain-source ON resistance		Pag (a)	$V_{GS} = -4 \text{ V}, I_D = -2.5 \text{ A}$	1	0.24	0.28	Ω
		R <sub>DS</sub> (ON)	$V_{GS} = -10 \text{ V}, I_D = -2.5 \text{ A}$	I	0.16	0.19	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -2.5 \text{ A}$	2.0	4.0	_	S
Input capacitano	e	C <sub>iss</sub>		1	630		
Reverse transfer	r capacitance	C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	95	_	pF
Output capacitance		C <sub>oss</sub>		_	290	_	
Switching time	Rise time	t <sub>r</sub>	$V_{\text{GS}} \stackrel{\text{OV}}{=} 10V$ $R_{\text{L}} = 12\Omega$ $V_{\text{DD}} = -30V$	_	25	_	
	Turn-on time	t <sub>on</sub>			45		ns
	Fall time	t <sub>f</sub>		1	55	1	
	Turn-off time	t <sub>off</sub>	Duty $\leq 1\%$ , $t_{\mathbf{W}} = 10 \mu \text{s}$	_	200	_	
Total gate charge (Gate-source plus gate-drain)		Qg	$V_{DD} \approx -48 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -5 \text{ A}$	_	22	_	
Gate-source charge		$Q_{gs}$		_	16	_	nC
Gate-drain ("miller") charge		$Q_{gd}$		- 1	6	_	

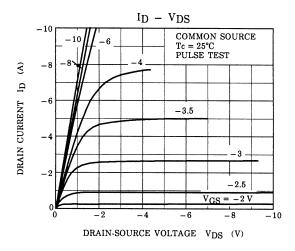
### Source-Drain Ratings and Characteristics (Ta = 25°C)

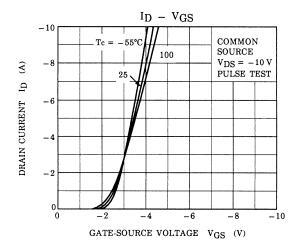
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	-5	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	-	-20	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = -5 A, V <sub>GS</sub> = 0 V	_	_	1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = -5 A, V <sub>GS</sub> = 0 V	1	80	_	ns
Reverse recovery charge	Qrr	dl <sub>DR</sub> / dt = 50 A / μS	_	0.1	_	μC

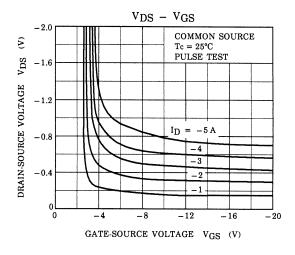
## Marking

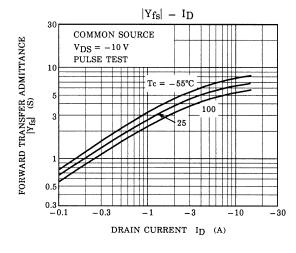


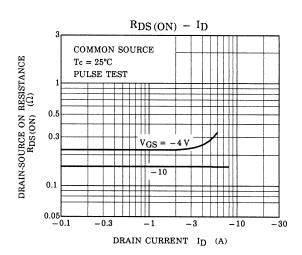




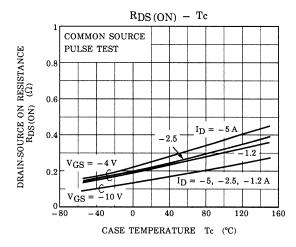


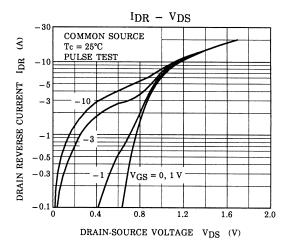


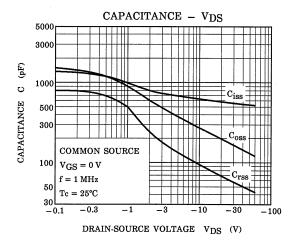


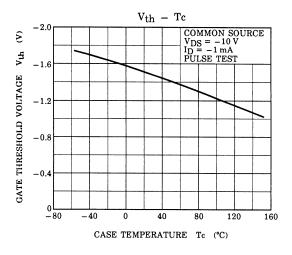


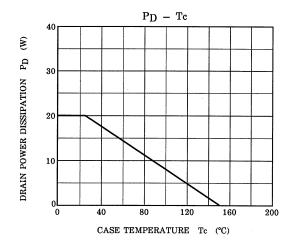
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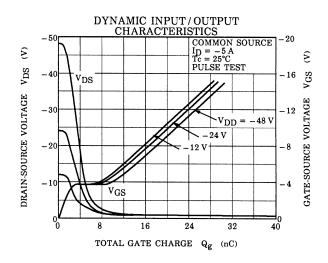




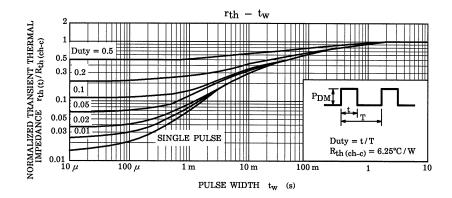


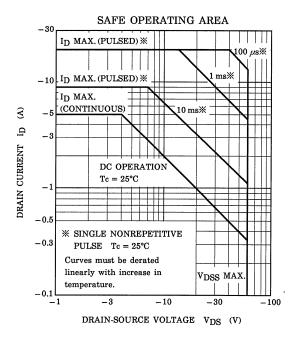


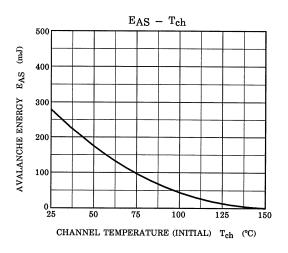


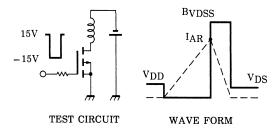


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$$\begin{array}{ll} R_G \!=\! 25\Omega \\ V_{DD} \!=\! -25V, \ L \!=\! 14.84 mH \end{array} \quad E_{AS} \!=\! \frac{1}{2} \cdot L \cdot I^2 \cdot (\frac{B_{VDSS}}{B_{VDSS} \!-\! V_{DD}} \end{array}$$

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